

### Designed for Simplicity and Reliability



LCR measurement of  
**008004** size\* SMDs

#### Compatible LCR instruments

IM3590, IM3570, IM3536, IM3533, IM3523, 3511-50, 3506-10  
3532-50 (legacy product), 3522-50 (legacy product)

\*EIA unit: inch  
(0.25 mm × 0.125 mm)

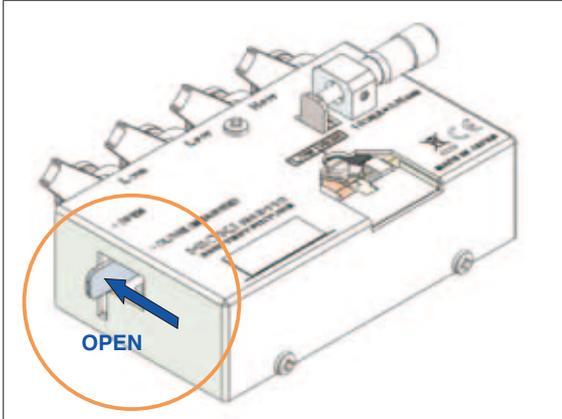


Information current as of March 2016. Please contact Hioki for the latest information about supported models.

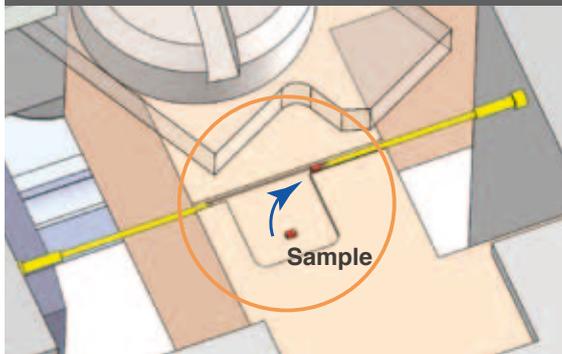
# Easily place samples via built-in cover that keeps the sample from popping out

## Loading samples

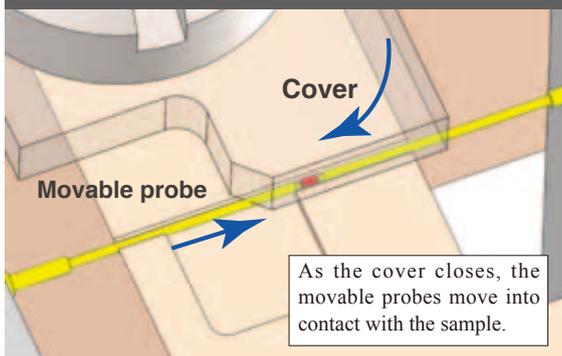
1. Move the control lever to the "OPEN" position.



2. Place the sample in the guide groove.

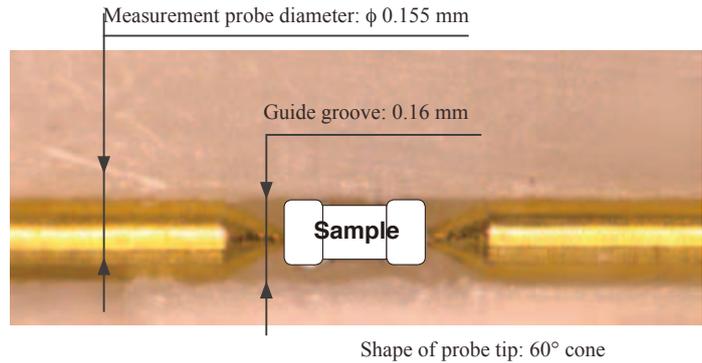


3. Move the control lever to the "CLOSE" position to lock the sample in place.



## Measurement by LCR meter

## Probe contact



Advanced contact technology delivers highly reproducible measurement results.

## Specifications

Operating temperature and humidity	0°C to 40°C (32°F to 104°F), 80% RH or less (no condensation)
Storage temperature and humidity	-10°C to 55°C (14°F to 131°F), 80% RH or less (no condensation)
Dimensions	Approx. 99 mm (3.9 in) W x 42 mm (1.65 in) H x 73 mm (2.87 in) D (Excluding control lever, lock lever, and micrometer)
Mass	Approx. 270 g (9.5 oz)
Product warranty	1 year
Connection with sample	2-terminal connection from opposite sides
Measurable sample dimensions	0.25 ±20% × 0.125 ±10% × 0.125 ±10% mm (EIA size category: 008004) Please contact Hioki for information about other sizes.
Maximum applied voltage	±42 V peak (AC+DC)
Maximum applied current	0.15 Arms (±0.15 A DC)
Usable frequency range	DC to 1 MHz
Residual parameter values (Reference values with a measurement frequency of 1 MHz)	<ul style="list-style-type: none"> <li>•Capacitance: C &lt; 35 fF (With 0.25 mm between measurement probes)</li> <li>•Inductance: L &lt; 120 nH (2-terminal contact while using short compensation fixture)</li> <li>•Resistance: R &lt; 800 mΩ (2-terminal contact while using short compensation fixture)</li> </ul>
Contact pressure on sample	0.14 N (15 gf) or less
Measurement probe distance setting	Set using a micrometer with a 0.01 mm graduated scale. (Inclusion of a micrometer allows the distance between measurement probes to be set easily. In particular, open compensation can be performed without a measurement sample.)
Connection to instrument	4-terminal pair (Connector: BNC; distance between connectors: 22 mm)
Accessories	User manual, short compensation fixture × 3, cleaning brush

Product Name: SMD TEST FIXTURE IM9110

Model No. (Order Code)  
IM9110

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**HIOKI**  
HIOKI E. E. CORPORATION

HEADQUARTERS  
81 Koizumi, Ueda, Nagano, 386-1192, Japan  
TEL +81-268-28-0562 FAX +81-268-28-0568  
http://www.hioki.com / E-mail: os-com@hioki.co.jp

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**TAISHIN**  
TAISHIN CORPORATION

태신상사 주식회사

서울특별시 서초구 강남대로 309 코리아비즈니스센터 1703호  
TEL 02-3474-0070 FAX 02-3474-0059